

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/702,186	LIU ET AL.	
Examiner	Art Unit	_
Legie Pascal	2612	

	SEARC	HED	
Class	Subclass	Date	Examiner

Class	Subclass	Date	Examiner
SEE SEAF	RCH NOTES	1/12/2007	LP

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	